Where power supply design meets collaboration

隔離式閘極驅動器概論

張巍,系統工程師 德州儀器



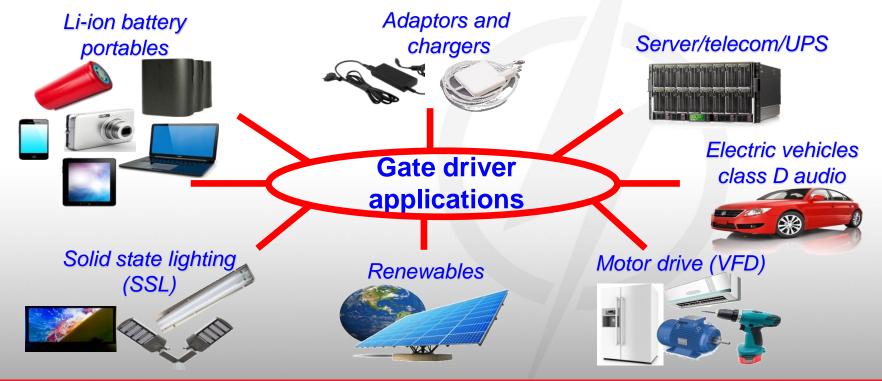
What will you get out of this session?

D PURPOSES:

- What are the gate driver application
- What are the differences: low-side, high-side and low-side, and isolated gate driver?
- How to maximize the gate driver performance from basic to details
 - Parasitics in the gate driver
 - Hard/soft switching
 - High dV/dt and di/dt
 - Isolated gate driver

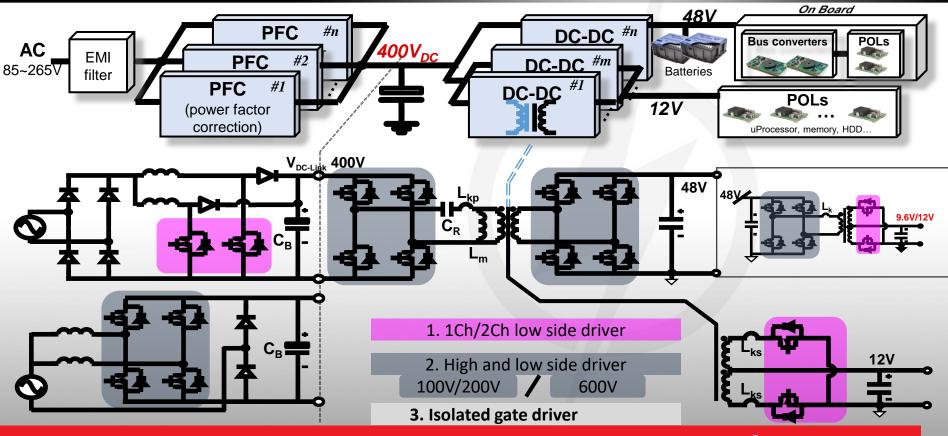
- Part numbers mentioned: Low side: UCC27511A, UCC27524A H-/L- Side: UCC27282, LMG1210, UCC27710 Isolated: UCC21540, UCC23513, UCC21710,
- Relevant End Equipment: Telecom, servers, solar inverters, motor drive, EV/HEV, UPS

Where are gate driver ICs used?

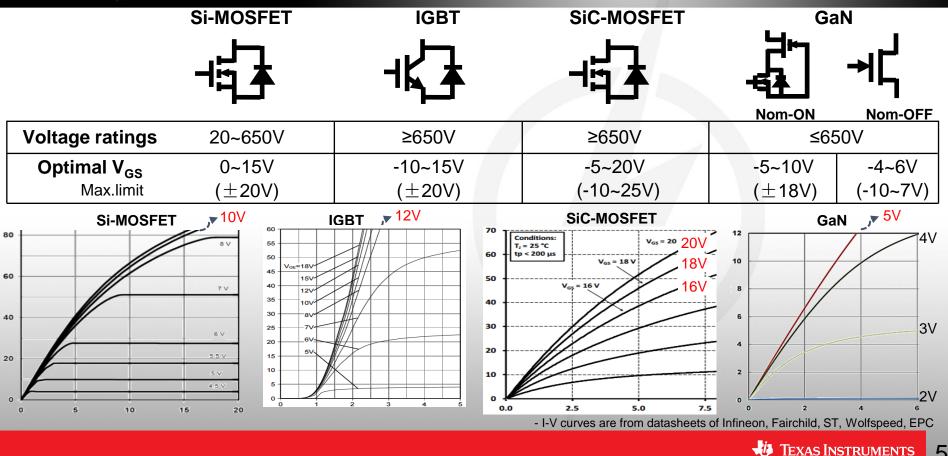




Gate Driver in Server / Telecom

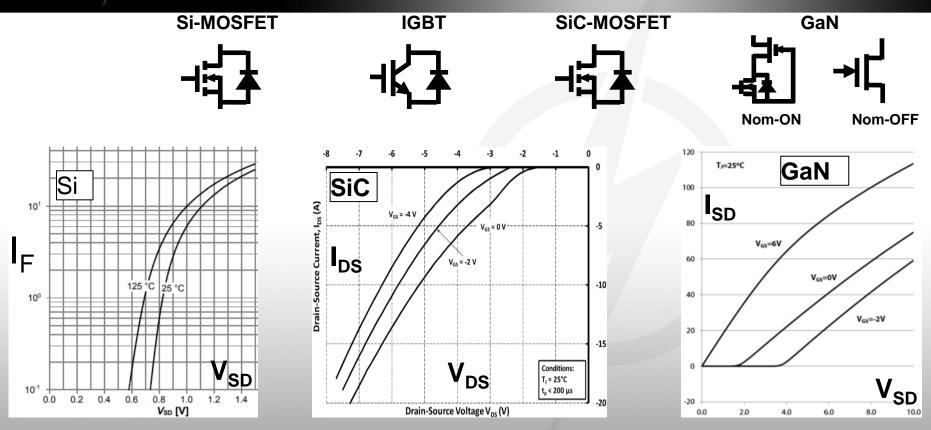


What are the Power Devices?



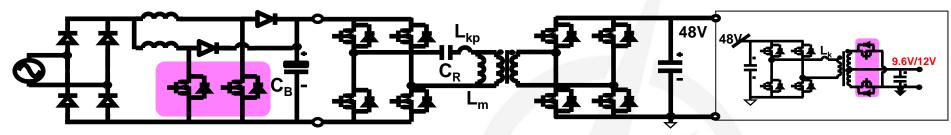
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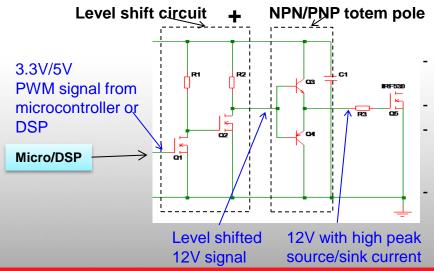
What are the Power Devices?



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Discrete vs Driver IC?





Reduces BOM component count

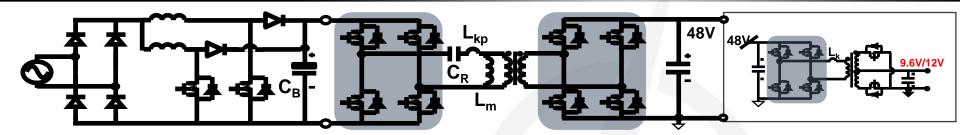
Now

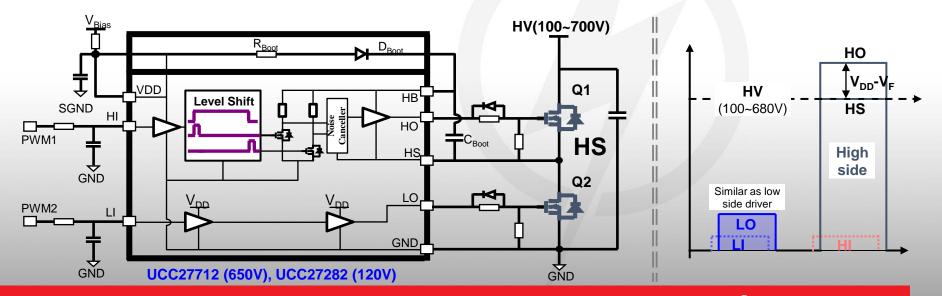
- **Reduces PCB space**
- Protects from spurious signals during power up (such as UVLO)
- Improves reliability



- UCC27511A Single
- UCC27524A Dual
- UCC27531 SiC or IGBT

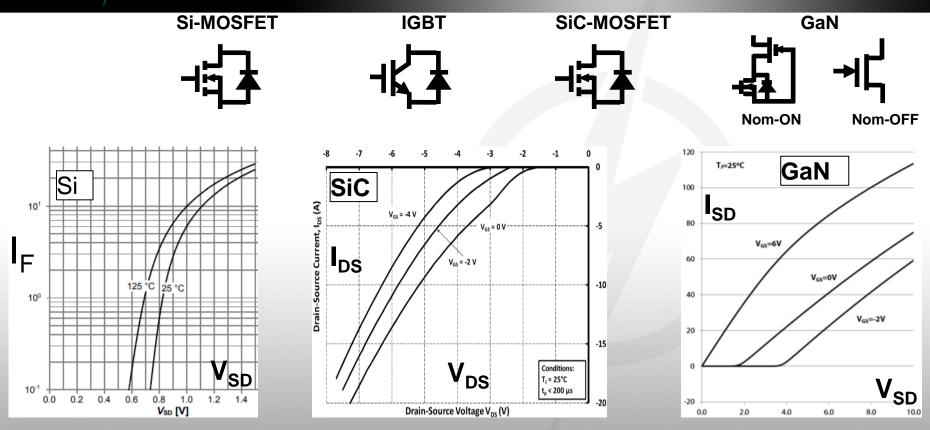
High VOLT Interactive How does a Half-Bridge Driver Operate?





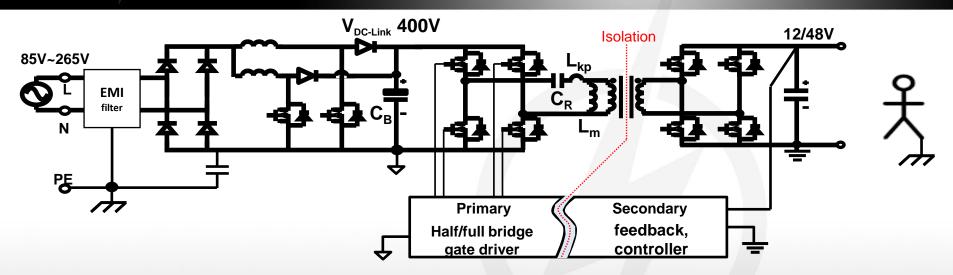
📲 Texas Instruments 🛛

What are the Power Devices?



🔱 TEXAS INSTRUMENTS

Why ISOLATION?



IEC	60950-1	ed. 2.0	, Table	5B
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	Test voltage for electric strength based on peak working voltage		
Working voltage V, peak o DC	Functional Isolation (V _{RMS})	Basic Isolation (V _{RMS})	Reinforced Isolation (V _{RMS})
≤210	1000	1000	1500
≤420	1500	1500	3000

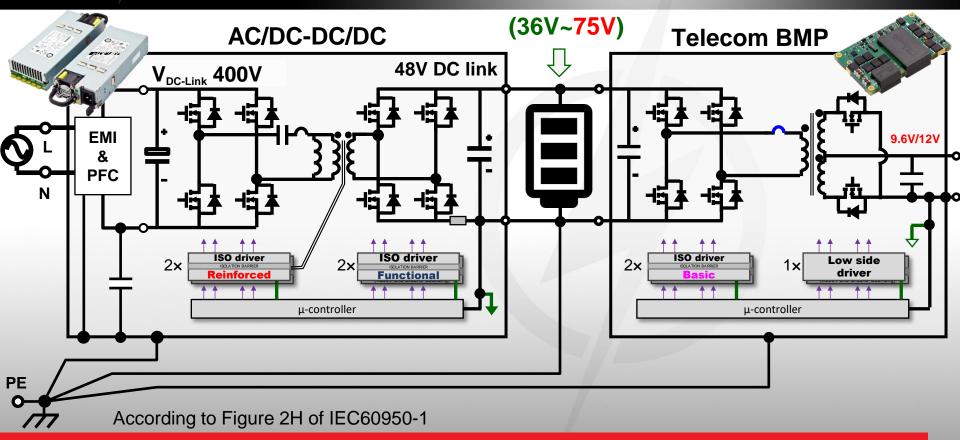


What is Functional, Basic, Reinforced Isolation?

Isolation	Definition	Featured Drivers
Functional	Isolation that is necessary only for the correct functioning of the equipment	UCC21220A, UCC21222
<u>Basic</u>	Isolation to provide basic protection against electric shock	UCC21220A, UCC21222
<u>Reinforced</u>	Single Isolation system that provides a degree of protection against electric shock equivalent to DOUBLE isolation under the conditions specified in this standard	UCC21540, UCC21520

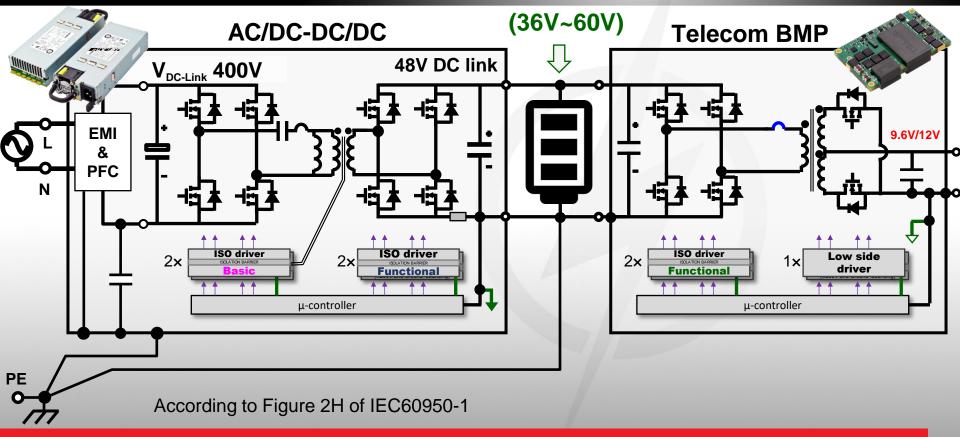


Isolation Req. Exp. per IEC-60950



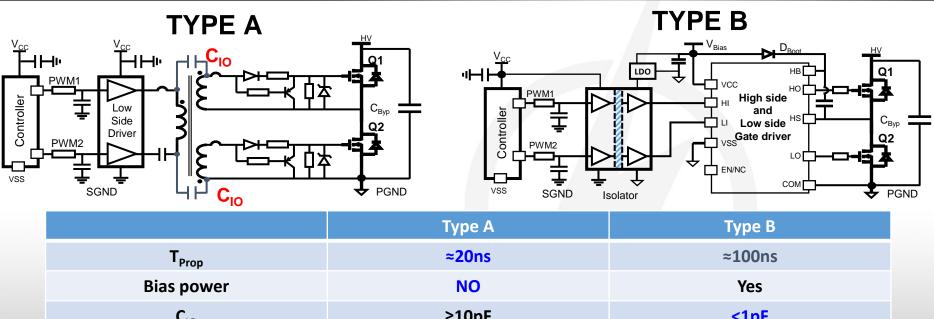
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Isolation Req. Exp. per IEC-60950



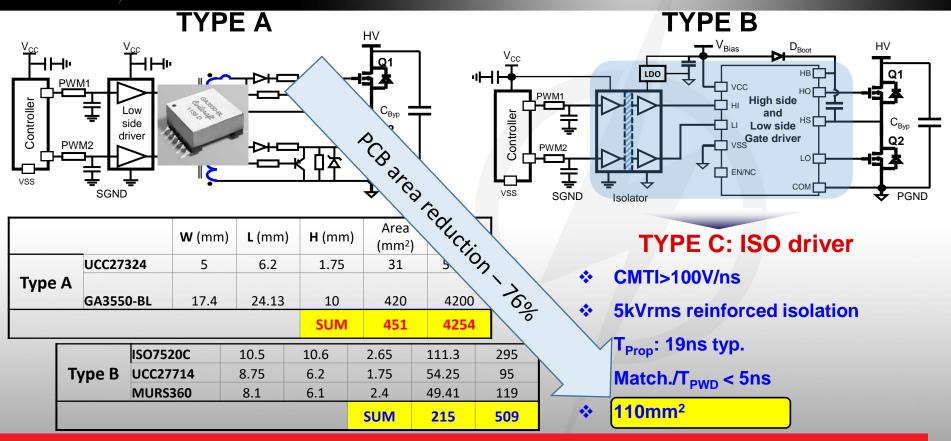
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Transformer vs. Driver IC



bias power	NU	res
C _{IO}	≥10pF	<1pF
Parasitics	Large (L _{LK})	Very small
Overshoot	Large	Small
Size	Bulky	Small

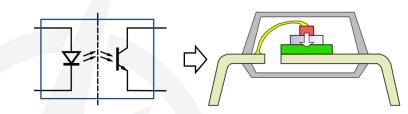
Transformer vs. driver IC?

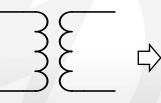


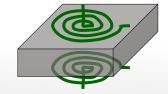
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Popular ISOLATION methods

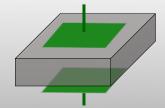
- A) Optocoupler
 - Signal transfer between two isolated circuits using light – LED + phototransistor, ~1970s
- B) Transformer
 - Integrated micro-transformer and electronic circuitry, ~2001
- C) Capacitor
 - Signal transmission through capacitive isolation with on-off-keying (OOK) modulation, ~2004



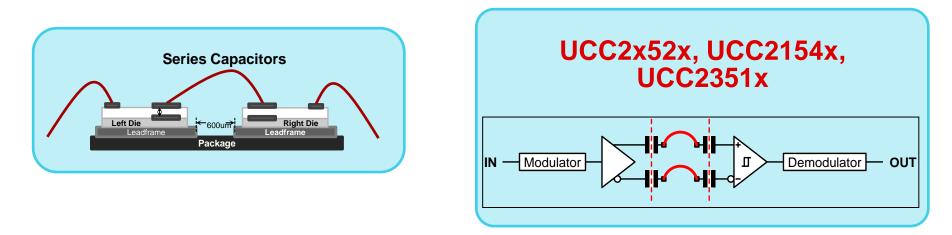








TI Reinforced Isolation Technology



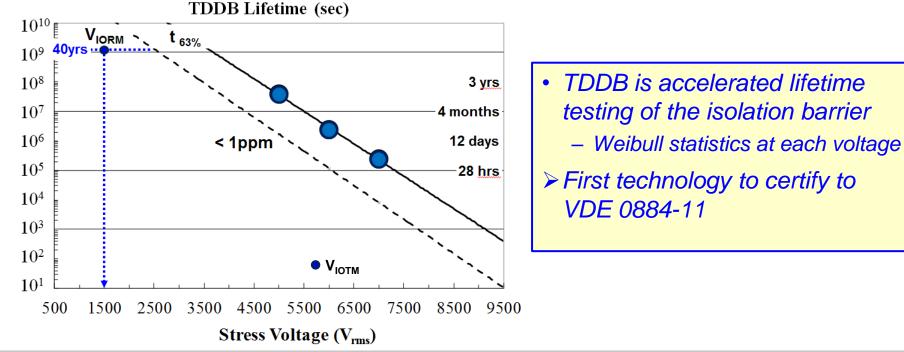
- Reinforced Isolation is realized by thick SiO₂ capacitors combined in series

 Each channel uses high voltage isolation capacitors on both die
- Combined Isolation capacitor thickness is >21um
- 12.8kV surge voltage, 8kVpeak transient over-voltage, 1.5kVrms working voltage



Foundation of Quality – Qualification & Reliability

- The main Isolation electrical lifetime test is TDDB: Qualification Test
 - Standard methodology for determining the lifetime of a dielectric as a function of Voltage



Texas Instruments

Foundation of Quality – SiO₂ Insulation

TI **Capacitive Isolation** uses SiO_2 as the Isolation Dielectric.

- SiO₂ advantages compared to competing HV isolative material are: reliability and dielectric strength

Insulator Materials	Dielectric Strength, 1 sec	Dielectric Strength, 40yr reliability
Air	~1 Vrms/um	
Epoxies	~20 Vrms/um	
Silica filled Mold compounds	~100 Vrms/um	
Polyimide	~300 Vrms/um	~20 Vrms/um
SiO ₂	~500 Vrms/um	~100 Vrms/um

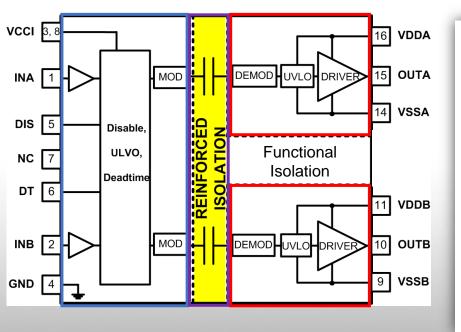
Table 1: Commonly used materials for High-Voltage isolation (SiO₂ has the highest dielectric strength and best reliability)

Dielectric Thickness (SiO₂) Fabrication Process Control & Monitor:

- **<u>Repeatability</u>** and <u>**Reproducibility**</u> SiO₂ thickness monitored using two methods:
 - Oxide thickness sample measured in the wafer fab for each of the layers of the dielectric stack
 - Tox by capacitance measurement on test structures on every production wafer after fabrication
- Thickness is tracked on all wafers for each fabrication lot as required by UL standard



UCC21220A, UCC21540: 2-ch. Isolated Gate Driver



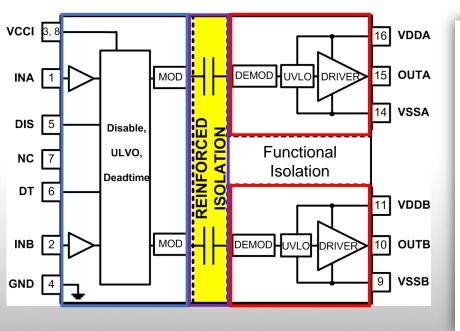
Input Die – takes inputs from µController, modulates and transmits across isolation barrier using on-off-keying

SiO2 Capacitors – provides high voltage basic or reinforced isolation, with excellent noise immunity and lifetime

Output Die – demodulates signal and drives outputs on or off depending on logic inputs

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UCC21220A, UCC21540: 2-ch. Isolated Gate Driver



- 6A/4A sink/source
- 28ns propagation delay
- >100V/ns CMTI
- Up to 3~5V input range and 6~18V wide output voltage range
- Programmable overlap, and interlock/delay time from 0ns~5µs

- Output fail safe low with active pull down
- UVLO options: 5V, 8V
- 3.0kV, 5.7kV basic/functional and reinforced isolation
- Pin-2-pin compatible to industry standard
- UL, VDE, CQC certified

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Integration

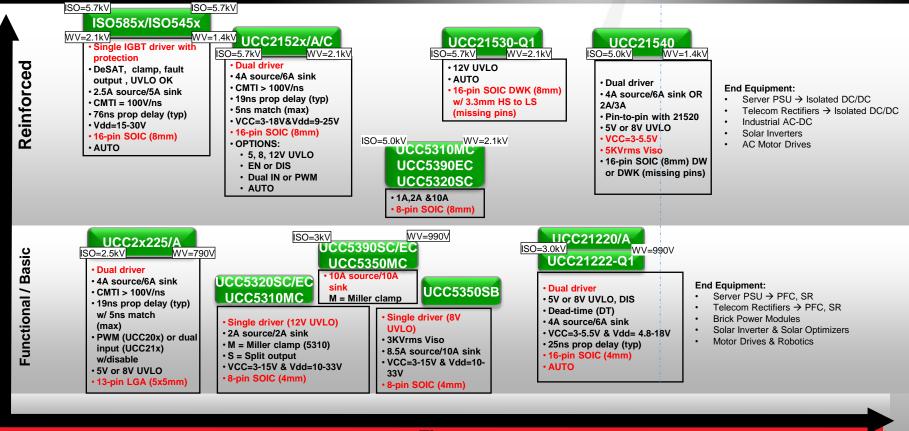
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Feature

Isolated Gate Driver Portfolio

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Main Differences UCC21520 & UCC21540

Parameter	UCC21520	UCC21540	Comments
VCCI/VDD AbsMax	20V _{CCI} /30V _{DD}	6V _{CCI} /20V _{DD}	UCC21540 – MOSFET
Output UVLO	5V, 8V, 12V	5V and 8V	
Pin 5 Functionality	DISABLE	DISABLE	UCC21540 – P2P w/ UCC21520
Driver-to-Driver Spacing	2mm	2mm & 3.3mm	3.3mm enables higher bus voltage safety standards
Propagation Delay	19ns typical	28ns typical	Allow accurate switching and fastest response - higher power density enabling smaller solutions
VDDA/VDDB UVLO startup delay	50µs typical	23µs typical	Easy synchronization between high side and low side
PCB modifications to accommodate for >600V DC Bus Voltage Applications	External coating on pins 12-13 (NC) to increase driver-to-driver working voltage Need Conformal Coating on System PCB for HV isolation	No changes required	UCC21540 enables: • Lower cost MOSFET Solution • No special coating required • Higher system reliability
Automotive Grade	AEC-Q100 available	N/A	



UCC23513 Specifications

4A, 5kV_{RMS}, Opto-Compatible Input Gate Driver in Stretched SO-6

Overview

UCC23513 is a 4A, $5kV_{RMS}$ opto-compatible gate driver available in stretched SO-6. Using capacitive isolation technology to simulate opto-isolation, this solution is more robust, longer-lasting, and exhibits exemplary propagation delay and Common Mode Transient Integrity specifications. With UCC23513, TI is providing customers with a pin-to-pin replacement for opto-isolated gate drivers to offer a better performing and longer-lasting solution that requires minimal effort to design in.

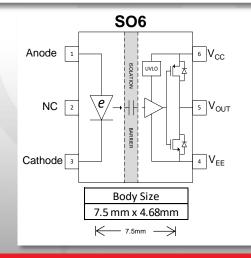
Features

- · Opto-compatible input, isolated Gate driver for IGBT/MOSFET/SiCs
- SiO₂ based capacitive isolation technology
- Pin compatible, drop-in upgrade for ACPL-W341, W346, TLP5752
- 4A peak output drive current
- 35V max output drive $(V_{CC} V_{EE})$
- SO6 (6 pin wide lead, smt), NiPdAu lead finish, material group I
- + > 8.5mm Cr & Clr; 5kV_{RMS} reinforced isolation
- 105ns propagation delay with 25ns part-to-part delay matching
- 100 kV/us Common Mode Transient Integrity (CMTI)
- 12V Under Voltage Lockout (UVLO)
- Input stage can be reverse-biased for interlock
- Wide operating temperature range (Tj): -40°C to 150°C

http://www.ti.com/product/UCC23513

Benefits

- Higher common mode transient integrity
- Smaller propagation delay and tighter part-to-part delay matching
- Lower pulse width distortion
- · Higher reliability, resistant to temperature and aging
- No long term aging of input stage
- Very tight tolerance of cap oxide since oxide is a controlled fab process
- Long lifetime (> 40 yrs)
- Less variation in forward current due to tighter V_F





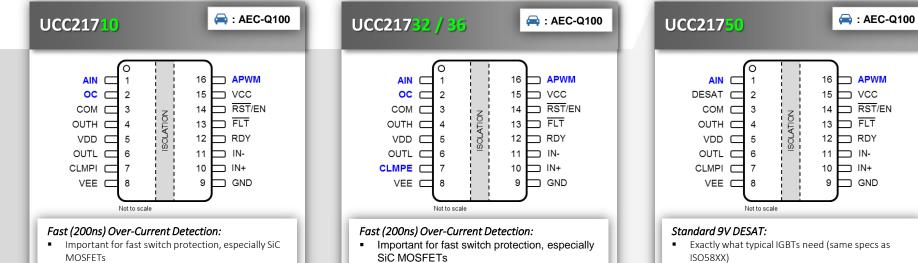
35° NOM

11.500 ±0.25

(0.453 ±0.010)

New Features in UCC217XX	Key System Challenge Solved		System Benefits
	IGBT	SiC	System benefits
±10A peak drive strength (throughout drive voltage range)	>10kW systems use discrete buffers (e.g., NPN+PNP) to increase drive strength: Reliability, drive supply & cost challenges		 Higher System Reliability + Higher Efficiency Lower System Cost + Smaller PCB Area
>150V/ns CMTI (Min)	(Typically <50V/ns)	SiC switches fast to reduce switching loss	Enhanced System RobustnessHigher System Efficiency
200ns Over-Current Detection + 650ns Isolated Fault Reporting	Programmable DESAT threshold voltage	SiC has <3µs short-circuit capability	Fast System ProtectionEnhanced System Robustness
2-Level Turn OFF (Option)	Significantly reduced V_{CE}/V_{DS} Overshoot during System Shutdown		 Safe System Shutdown Enhanced System Robustness Improved Switch Lifetime
Integrated Isolated Accurate Analog-to-PWM Sensor	Eliminate all discrete components used for bus voltage sensing / switch temperature sensing / sec-to-primary feedback / isolated alarm /		Lower System CostSmaller PCB Area
VEE UVLO (Option)	Eliminate discrete circulity for VEE monitoring (voltage sensor + isolator)		Lower System CostSmaller PCB Area
External Miller Clamp (Option)	More effective technique than internal miller clamp for high-power switch modules		Enhanced System RobustnessLower System Noise (Ringing + EM)
Standard SOIC-16 DW Package	Small package size, 1mm pad pitch, pin-to-pin compatibility with better specs		Lower System CostSmaller PCB Area





- Allows for flexible DESAT threshold setting for SiC MOSEET or IGBT
- Applicable to IGBT modules with SenseFET .

Internal Miller Clamp: Suited for lower power levels (<50kW) or tighter layouts (driver to switch)

Soft Turn-OFF: Preferred method for safe shutdown of SiC or IGBT switch

- Allows for flexible DESAT threshold setting for SIC MOSEET or IGBT
- Applicable to IGBT modules with SenseFET

External Miller Clamp: Ideal for high-power IGBT/SiC modules (reduce clamp-to-gate parasitics)

2-Level Turn-OFF: Preferred for high-power modules for higher power applications

 9V DESAT might be high for SiC MOSFETs (depends) on SiC MOSFET supplier)

Internal Miller Clamp: Suited for lower power levels (<50kW) or tighter layouts (driver to switch)

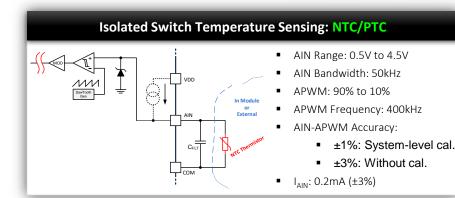
Soft Turn-OFF: Preferred method for safe shutdown of IGBT or SiC switch

[NOTE: Pins in Black have same pin locations as in ISO5852S or ISO5452. Pin in Blue are new pin definitions.]

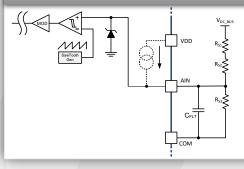


APWM

[Disclaimer: Specs, features & pinouts subject to change without prior notice.]

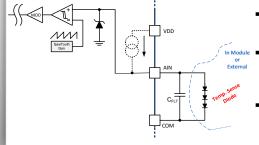


Isolated Analog Signal Sensing: HV Bus / Power Supply / ...



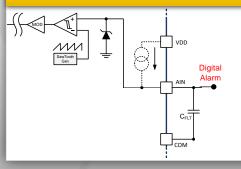
- HV Bus Sensing
- Secondary-to-Primary Bus Voltage Feedback
- Driver-side Supply Voltage Monitoring (Redundant / Additional UVLO)

Isolated Switch Temperature Sensing: Thermal Diode



- Switch Over-temperature Detection: System Protection
- System performance optimization based on Switch Temperature Sensing
- Switch temp-cycling / lifetime monitoring

Isolated Digital Signal: Alarm / Shutdown

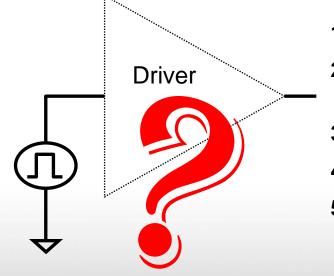


- Digital Alarm
- Emergency Shutdown signal





Gate Driver Design is Simple?



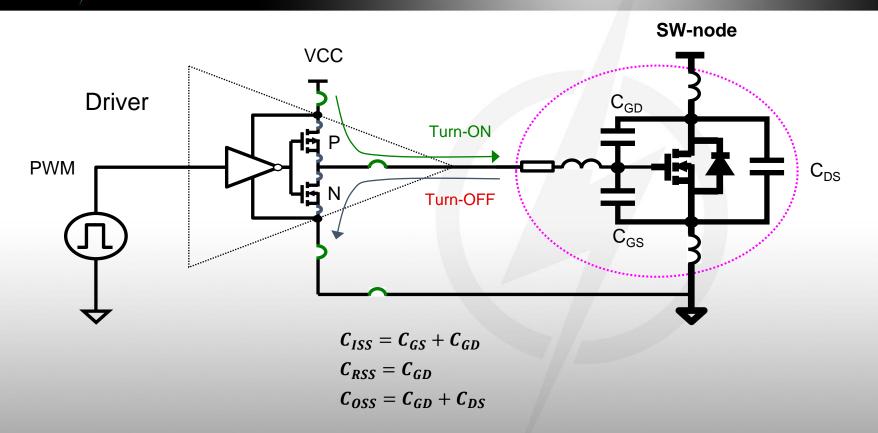
- 1. Parasitics in gate driver?
- 2. Common mode transient immunity(CMTI), dv/dt and di/dt through parasitics L and C?
- 3. Gate driver soft/hard switching difference?
- 4. Strong gate driver and MOSFET nonlinear Coss?
- 5. Power supply for isolated gate driver in UPS, server and Telecom system

Gate driver deep dive

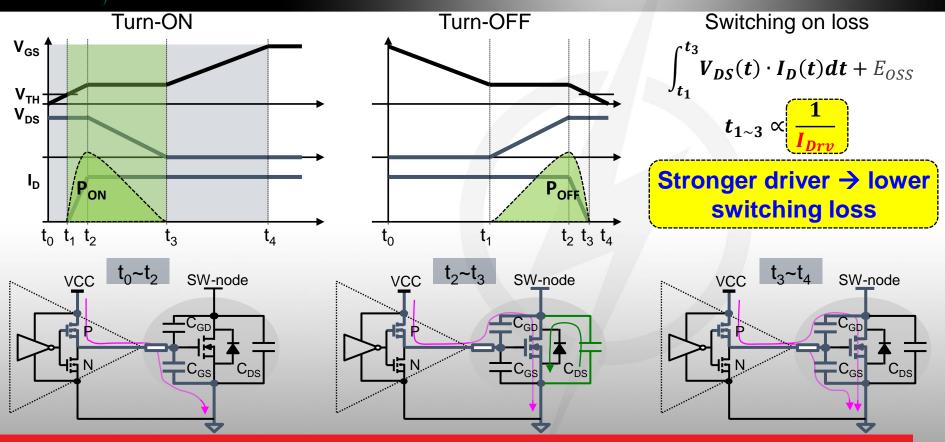
Very critical role in converter efficiency and reliability



What are the Parasitics?

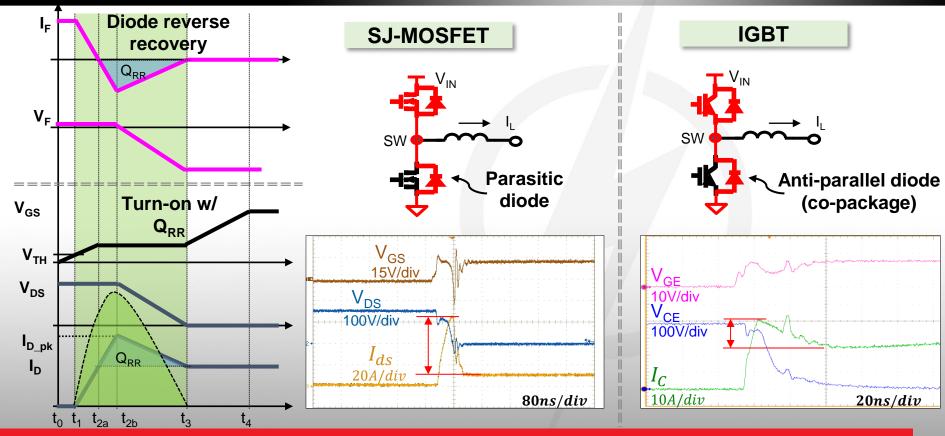


Turn-ON/OFF process

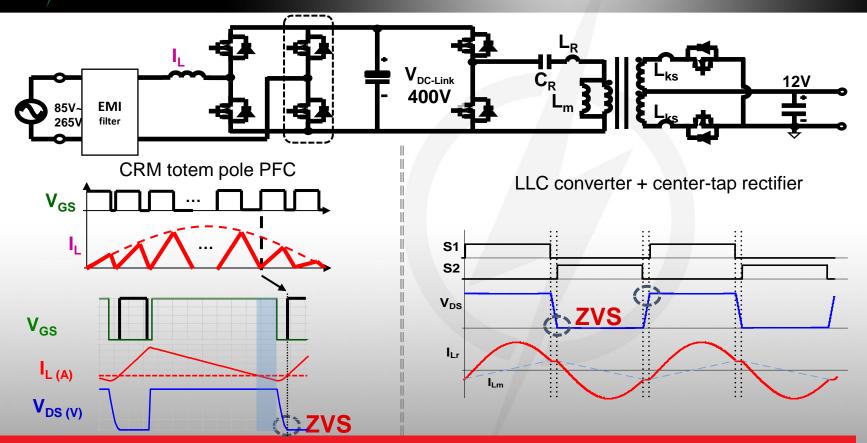


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Turn-ON with Reverse Recovery

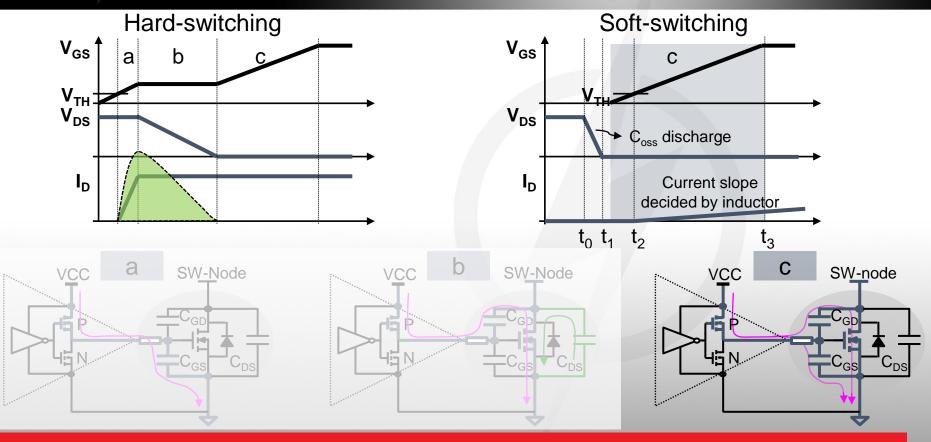


Soft Switching



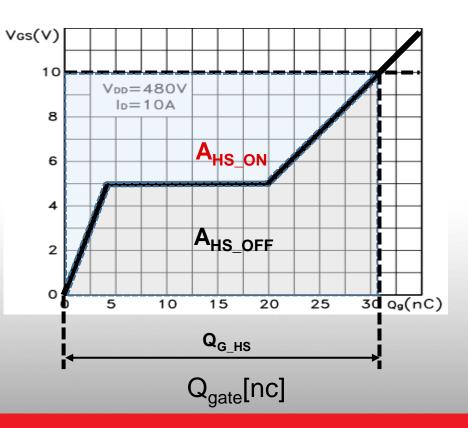


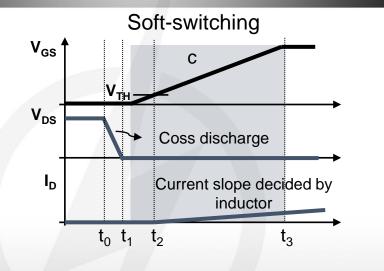
Gate Driver for Soft Switching



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Gate Driver for Soft Switching



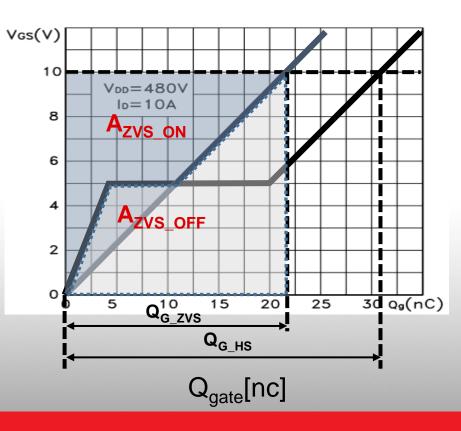


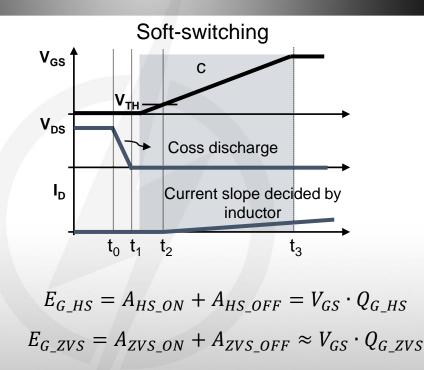
 $E_{G_HS} = A_{HS_ON} + A_{HS_OFF} = V_{GS} \cdot Q_{G_HS}$

$$P_{GateDrv} = E_G \cdot f_{SW}$$



Gate Driver for Soft Switching

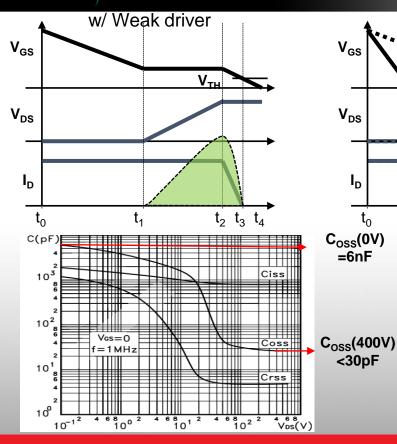


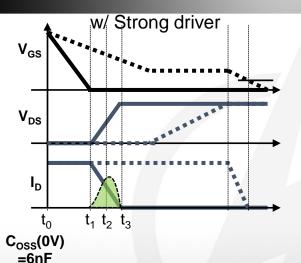


 $P_{GateDrv} = E_G \cdot f_{SW}$

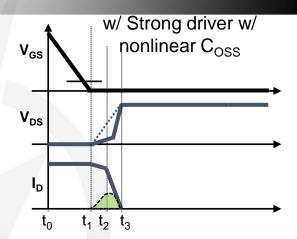
V TEXAS INSTRUMENTS 35

Strong Turn-OFF





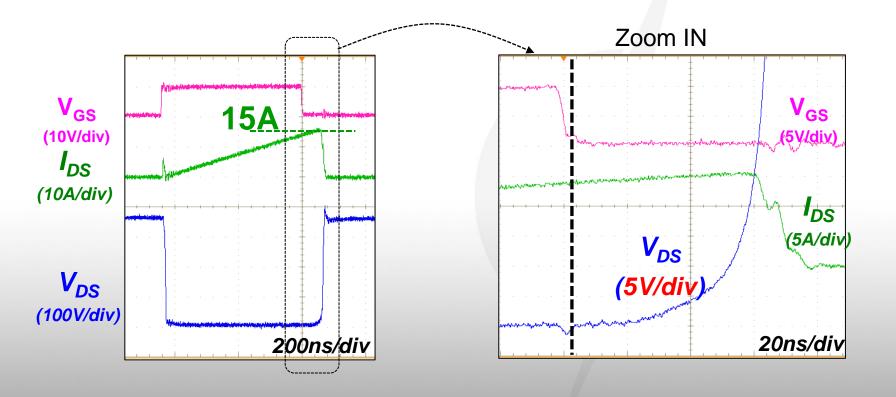
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- Switching behavior is not controlled by gate current, but by Coss and load current
 - Large C_{oss} at low voltage performs as natural snubber
- Small C_{oss} at high voltage shortens V-I overlap
- Fast dv/dt and di/dt, other bad things

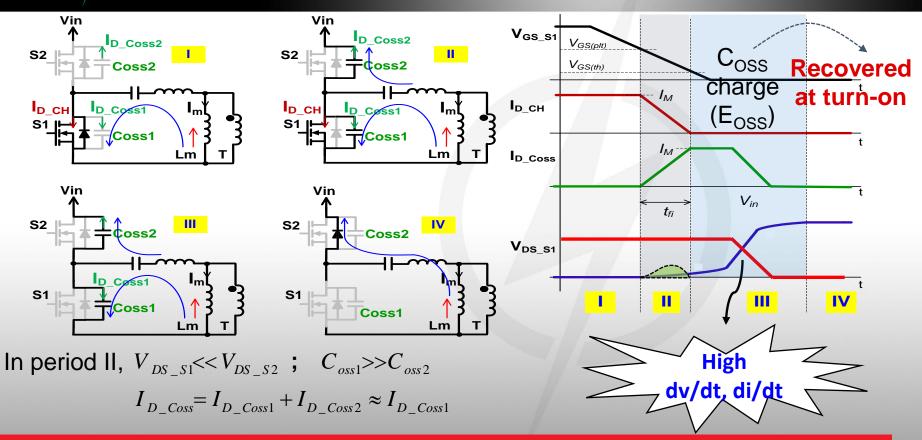


Strong Turn-OFF



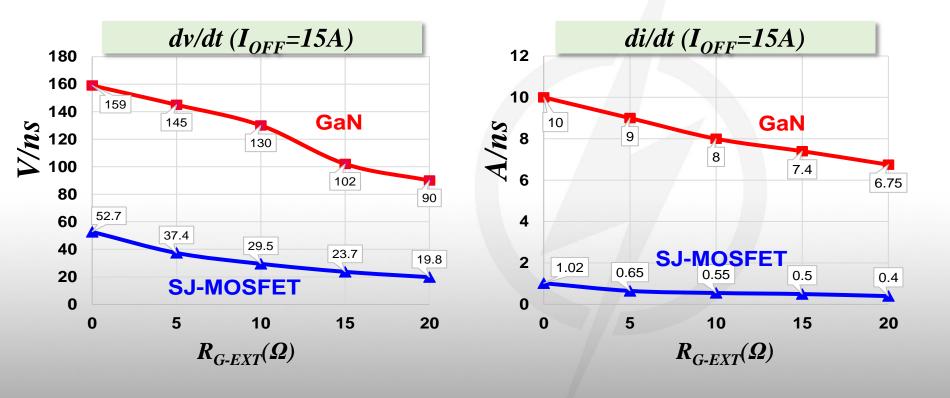
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Strong Driver for LLC Turn-OFF



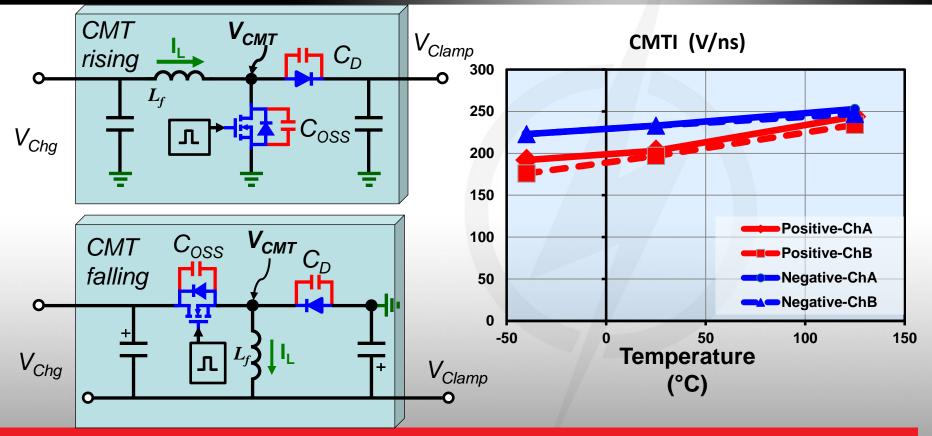


High dv/dt and di/dt: GaN vs. Si

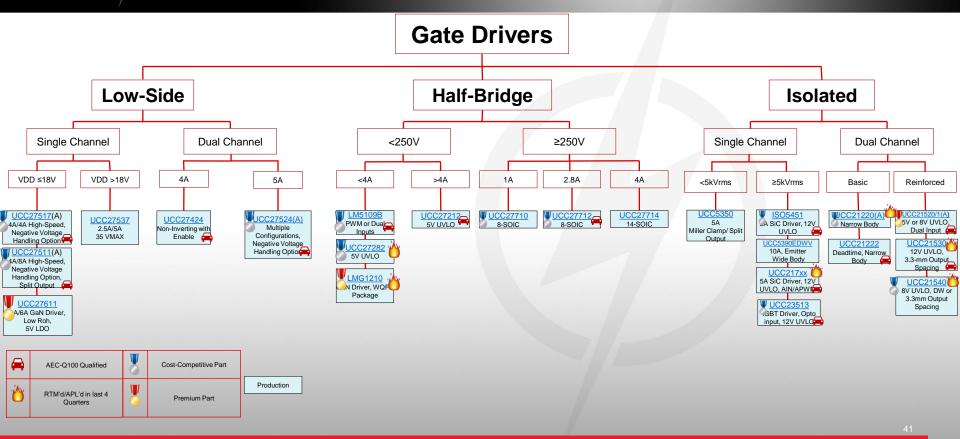


V TEXAS INSTRUMENTS 39

CMTI Measurement for UCC21540



Gate Driver Portfolio: Selection Tree



Low-Side Drivers

idge Drivers

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Summary

- Gate driver fundamentals and in-system consideration
- Low side, high- and low side, isolated gate driver
- □ Parasitics in gate driver?
- Gate driver soft/hard switching difference?
- □ Strong gate driver and MOSFET nonlinear C_{OSS}?
- Common mode transient immunity(CMTI), dV/dt and di/dt through parasitics
- D Power supply for isolated gate driver in UPS, server and Telecom

Sample TI's New Isolated Gate Drivers:
 UCC21540: <u>http://www.ti.com/product/UCC21540/samplebuy</u>
 UCC21220A: <u>http://www.ti.com/product/UCC21220A/samplebuy</u>
 UCC21710-Q1: <u>http://www.ti.com/product/UCC21710-Q1/samplebuy</u>
 UCC23513: <u>http://www.ti.com/product/UCC23513/samplebuy</u>

Summary





